Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/052,113	LEE ET AL.
Examiner	Art Unit
Krista M. Flanagan	2631

SEARCHED				
Class	Subclass	Date	Examiner	
375	211 214 215 354 371 373 355	4/6/2005	KMF	
327	164 201	4/6/2005	KMF	
327	291 385	4/6/2005	KMF	
327	386	4/6/2005	KMF	
,				

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

	RCH NOTES EARCH STRATEGY)
	DATE	EXMR
EAST (Bocure)	4/6/2005	KMF
Inventorship	4/6/2005	KMF
EAST	4/14/2005	KMF